

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/625,631	ITO ET AL.	
Examiner	Art Unit	
Sun J Lin	2825	

SEARCHED					
Class	Subclass	Date	Examiner		
716	11	3/13/2007	JSL		
716	8	3/13/2007	JSL		
716	9	3/13/2007	JSL		
716	10	3/13/2007	JSL		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
716	8,9	3/13/2007	JSL		
716	10,11	3/13/2007	JSL		
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(INCLUDING SEARCH		
<u> </u>	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	3/13/2007	JSL
GOOGLE	3/13/2007	JSL